



Substitute for form 1449A/PTO

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Complete if Known

Application Number	10/824,285
Filing Date	April 14, 2004
First Named Inventor	Ratliff, Bradley
Group Art Unit	2884
Examiner Name	Taningco, Marcus

Sheet 1 of 6

Attorney Docket No: 1863.070US1

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M. Taningco

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Substitute Disclosure Statement Form (PTO-1449)

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